

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of: Tapan J. Chakraborty and Chen-Huan Chiang

Application No: 10/648,055

Confirmation No: 2959

Filed: August 26, 2003

Group Art Unit: 2113

For: Fault Injection Method and System

Examiner: Wilson, Yolanda L.

M.S.
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

DECLARATION IN LIEU OF AN AFFIDAVIT UNDER 37 C.F.R. 1.131

I, Tapan J. Chakraborty, and I, Chen-Huan Chiang, declare as follows:

(1) We are the named inventors in our U.S. Patent Application No. 10/648, 055, filed 08/26/2003.

(2) We are the authors of the technical paper: Chakraborty, Tapan J. and Chiang, Chen-Huan, "A Novel Fault Injection Method for System Verification Based on FPGA Boundary Scan Architecture," ITC INTERNATIONAL TEST CONFERENCE, Paper 32.1, Pages 923-929, October 2002.

(3) The technical paper, identified in paragraph (2.) above, expressly names us, Chakraborty, Tapan J. and Chiang, Chen-Huan, as being the authors of the technical paper.

(4) The technical paper paper, identified in paragraph (2.) above, is a printed publication, and is not a patent.

(5) We are both the authors of the technical paper, identified in paragraph (2.) above, and the named inventors of our U.S. Patent Application No. 10/648, 055, filed 08/26/2003.

(6) We caused the publication of the technical paper, identified in paragraph (2.) above, less than one year prior to the filing date of 08/26/2003 of our U.S. Patent Application No. 10/648, 055.

(7) Any invention disclosed in the technical paper, identified in paragraph (2.) above, was disclosed by us as the authors of the technical paper, and is not the invention of another.

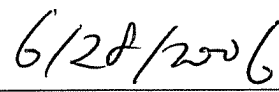
I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Tapan J. Chakraborty

Date



Chen-Huan Chiang



Date

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of: Tapan J. Chakraborty and Chen-Huan Chiang

Application No: 10/648,055

Confirmation No: 2959

Filed: August 26, 2003

Group Art Unit: 2113

For: Fault Injection Method and System

Examiner: Wilson, Yolanda L.

M.S.
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

DECLARATION IN LIEU OF AN AFFIDAVIT UNDER 37 C.F.R. 1.131

I, Tapan J. Chakraborty, and I, Chen-Huan Chiang, declare as follows:

- (1) We are the named inventors in our U.S. Patent Application No. 10/648, 055, filed 08/26/2003.
- (2) We are the authors of the technical paper: Chakraborty, Tapan J. and Chiang, Chen-Huan, "A Novel Fault Injection Method for System Verification Based on FPGA Boundary Scan Architecture," ITC INTERNATIONAL TEST CONFERENCE, Paper 32.1, Pages 923-929, October 2002.
- (3) The technical paper, identified in paragraph (2.) above, expressly names us, Chakraborty, Tapan J. and Chiang, Chen-Huan, as being the authors of the technical paper.

(4) The technical paper paper, identified in paragraph (2.) above, is a printed publication, and is not a patent.

(5) We are both the authors of the technical paper, identified in paragraph (2.) above, and the named inventors of our U.S. Patent Application No. 10/648, 055, filed 08/26/2003.

(6) We caused the publication of the technical paper, identified in paragraph (2.) above, less than one year prior to the filing date of 08/26/2003 of our U.S. Patent Application No. 10/648, 055.

(7) Any invention disclosed in the technical paper, identified in paragraph (2.) above, was disclosed by us as the authors of the technical paper, and is not the invention of another.

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Tapanjyoti Chakraborty.
Tapan J. Chakraborty

July 3, 2006
Date

Chen-Huan Chiang

Date